



Das Elektronik I Team

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- „Multisim 14“ Simulationsprogramm



- homepage:

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Stabilization and precise calibration of a continuous-wave difference frequency spectrometer by use of a simple transfer cavity

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A novel, simple, and inexpensive calibration scheme for a continuous-wave difference frequency spectrometer is presented, based on the stabilization of an open transfer cavity by locking onto the output of a polarization stabilized HeNe laser. High frequency, acoustic fluctuations of the transfer cavity length are compensated with a piezoelectric transducer mounted mirror, while long term drift in cavity length is controlled by thermal feedback. A single mode Ar⁺ laser, used with a single mode ring dye laser in the difference frequency generation of 2–4 μm light, is then locked onto a suitable fringe of this stable cavity, achieving a very small long term drift and furthermore reducing the free running Ar⁺ linewidth to about 1 MHz. The dye laser scan provides tunability in the difference frequency mixing process, and is calibrated by marker fringes with the same stable cavity. Due to the *absolute* stability of the marker cavity, precise frequency determination of near infrared molecular transitions is achieved via interpolation between these marker fringes. It is shown theoretically that the residual error of this scheme due to the dispersion of air in the transfer cavity is quite small, and experimentally that a frequency precision on the order of 1 MHz per hour is routinely obtained with respect to molecular transitions.

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Stabilization of the Difference Frequency Spectrometer

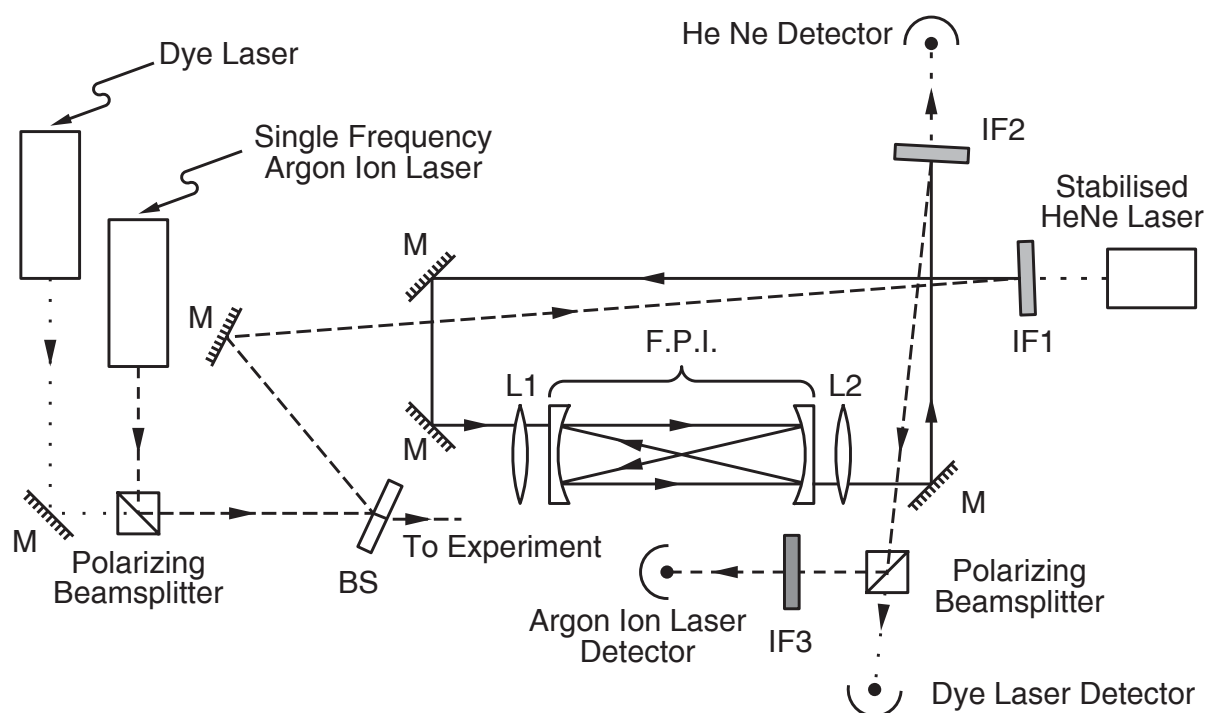
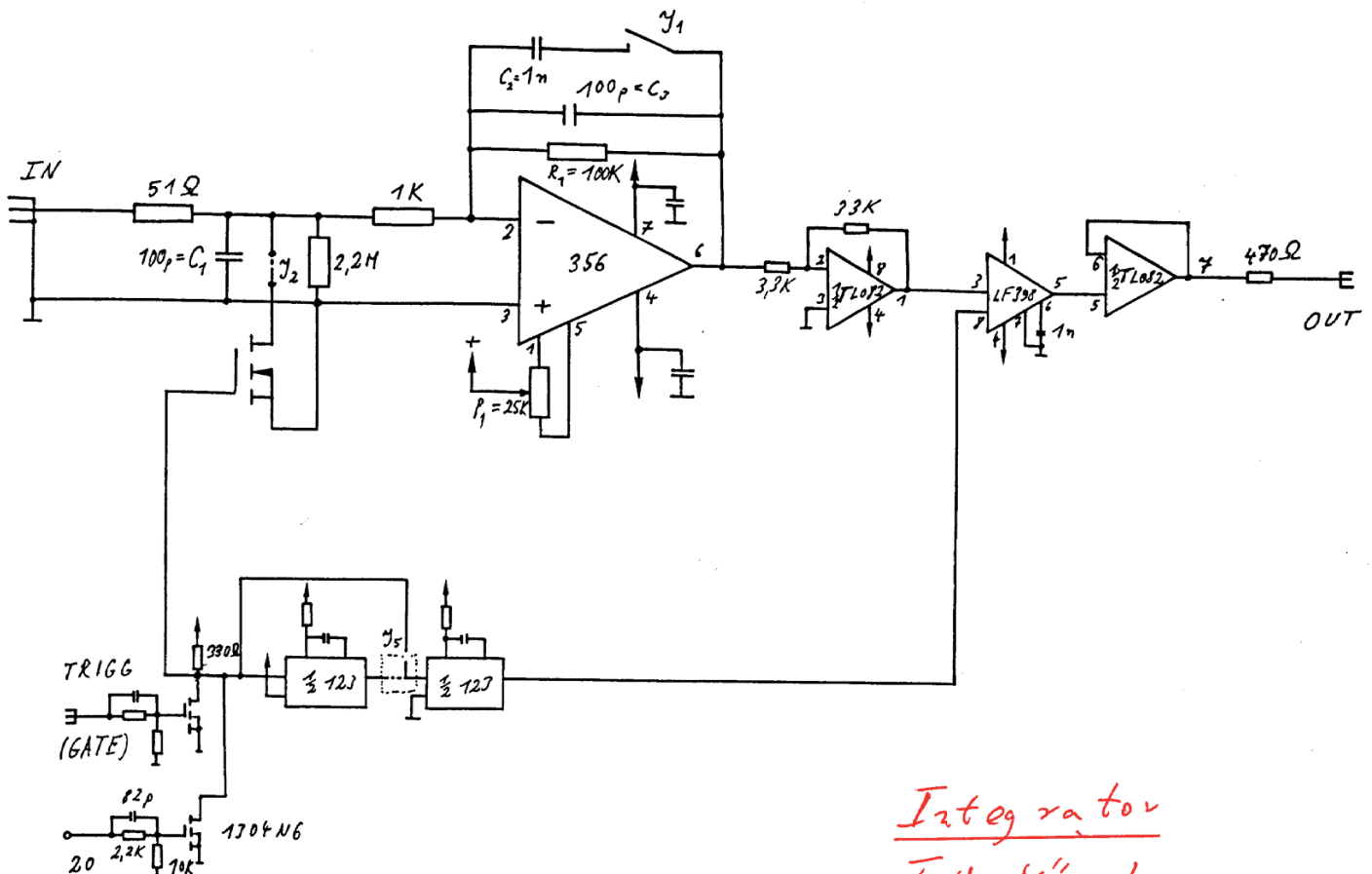
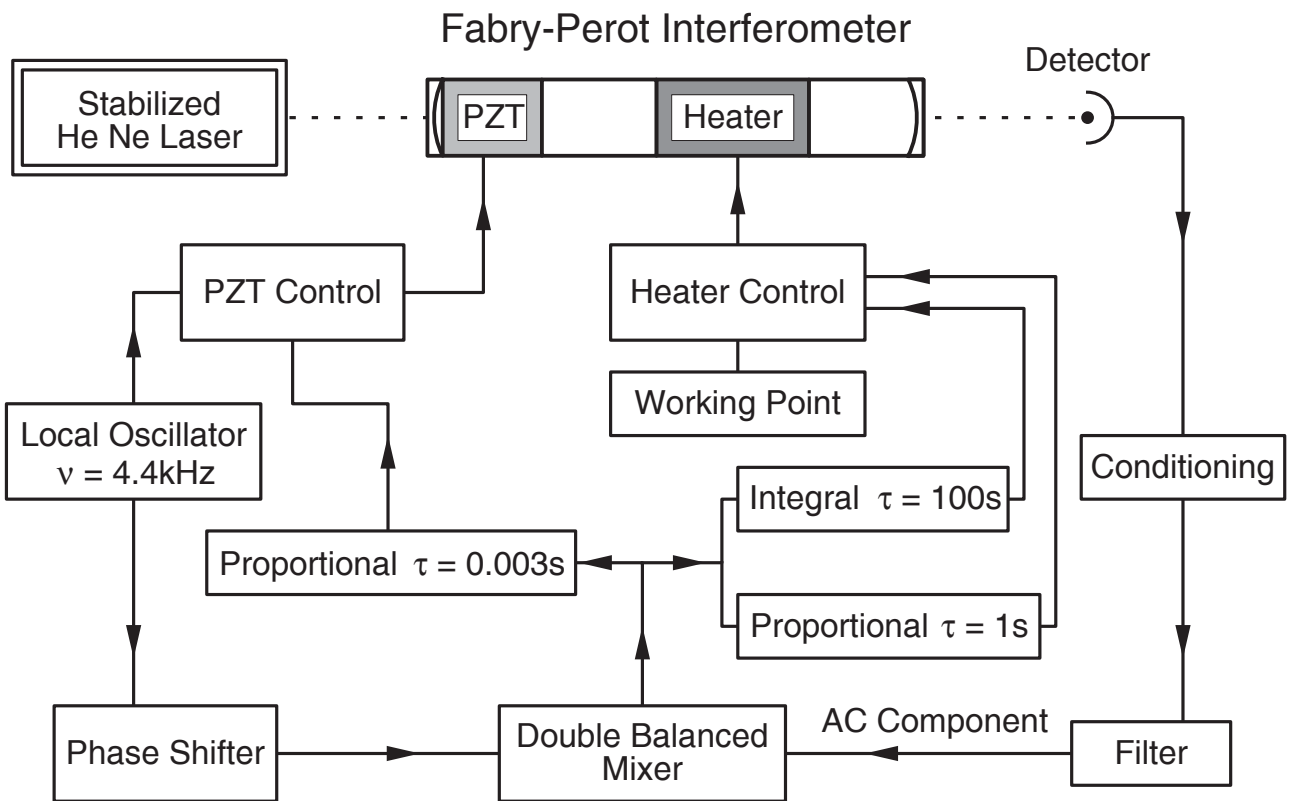


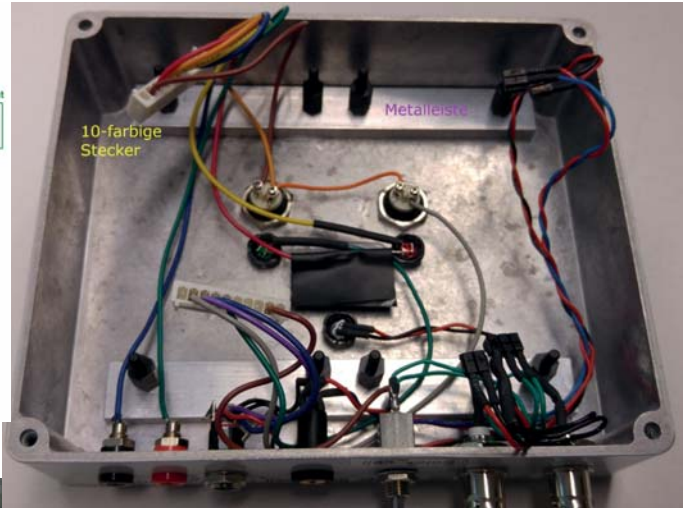
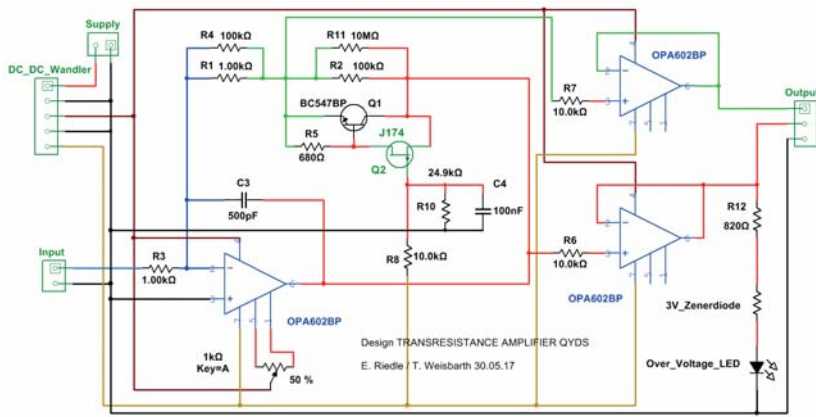
figure 1 E. Riedle et al., 'Stabilization and ...'

Locking of The Transfer Cavity



Integrator
 TU München
 Physikalische Chemie

QYDS electronics : shutter control and I/U converter for solar cell



Elektronik I, WS 2017/18 (E. Riedle)

0. Vorstellung und Einleitung

I. Lineare passive Bauelemente

- 1) Grundbegriffe, Widerstände, Kondensatoren, Spulen
- 2) Lineare Netzwerke - Reduzierung, Wheatstone'sche Brücke
- 3) Komplexe Amplituden in linearen Netzwerken
- 4) Anwendungen und Beispiele - Filterschaltungen, Schwingkreise

II. Netzwerke mit aktiven Bauelementen

- 1) Aktive Bauelemente - Spannungs- und Stromquelle, Ersatzschaltbilder
- 2) Zweipolquelle
- 3) Kreisstromverfahren, Knotenspannungen, Numerische Verfahren
- 4) Vierpole - Transformator, Vierpol- oder Filterkette
- 5) Leitungen, HF-Leitungen, Leitungstransformator etc.
 - Reflexion, Transmission
 - Anwendungen: kurze Pulse, Impedanztransformatoren
 - Oberflächenwellen, HF-Filter

III. Messtechnik und Schaltungssimulation

IV. Halbleiterbauelemente

- 1) Einleitung mit Kurzübersicht
 - Halbleiter, Dotierung, p-n Übergang
 - Shockley-Gleichung, Durchbruchmechanismen
- 2) Dioden - Kennlinienaufnahme etc.
 - NF Dioden: Gleichrichterdiode, Kapazitätsdiode, Z-Diode, Spannungsregler
 - HF Dioden: Oszillatoren, Tunneliode, Backwarddiode, pin-Diode
- 3) Transistoren
 - pnp / npn Transistor, Kennlinien, Arbeitspunkt
 - Grundsaltungen: Emitterschaltung, Kollektorschaltung, Basisschaltung
 - Verstärkung: Ruhestromeinstellung, Kleinsignalverstärkung
 - Strom-/Spannungs-Gegenkopplung, Bootstrapping
 - zweistufiger Verstärker, Differenzverstärker, Darlington-Stufe
 - Transistor als Schalter - ohmsche Last, kapazitive Last, induktive Last
 - FET's: JFET, MOSFET, HEMT, Thyristor, Triac
 - Dimmer, Analogschalter
 - Spannungsregler, Netzteile, Konstantstromquelle

V. Integrierte Schaltungen / Operationsverstärker (OPAMP)

- 1) Aufbau (3 Stufen) und Funktionsweise
- 2) Herstellung integrierter Schaltungen
- 3) Betriebsarten des OPAMP, Mit- und Gegenkopplung, Übertragungskennlinie, reale OPAMPs, Auswahl für praktische Anwendungen
- 4) Übertragungs- charakteristik:
 - Spannungsverstärker (invertierend / nichtinvertierend)
 - Rechenschaltungen: Addierer, Subtrahierer, Differenzierer
 - Integrierer, Logarithmierer, Delog., Wurzel, etc.
 - Komparator, Schmitt-Trigger, Sample&Hold
 - U/I Converter, I/U Converter
 - "gated" Integrator (Beispiel; Anwendung)
 - aktive Filter, Instrumentenverstärker
 - Hochspannungsverstärker (Beispiel)
 - Funktionsgeneratoren
 - hochstabile Netzteile
 - Schaltungen mit dem Zeitgeber "555"

VI. Steuerung und Regelung

- 1) Grundlagen, Zweipunktregler, Dreipunktregler, Bode - Diagramm (Stabilität)
- 2) Elemente des Regelkreises: Regelstrecke, Meßglied, Stellglied, Regler
- 3) PID - Regler, Einstellung
- 4) Beispiel: Fabry-Perot-Stabilisierung
- 5) PLL (phase-locked-loops)

VII. Optoelektronische Bauelemente

- 1) Photowiderstände
- 2) Photodioden, -transistoren; Differenzdetektion
- 3) Photomultiplier
- 4) Leuchtdiode, Diodenlaser
- 5) Optokoppler
- 6) Anzeigen
- 7) Akustooptische und elektrooptische Modulatoren

Literatur

1. U. Tietze, Ch. Schenk: " Halbleiterschaltungstechnik "
2. P. Horowitz, W. Hill: " The Art of Electronics "
Horowitz/Hill: "Die Hohe Schule der Elektronik 1 + 3 " (nur gebraucht verfügbar)
3. E. Hering, K. Bressler, J.Gutekunst: " Elektronik für Ingenieure "
4. H. Hartl, E. Krasser, G. Winkler, W. Pribyl, P. Söser: "Elektronische Schaltungstechnik"

Multisim 14: National Instruments
<http://www.ni.com/multisim/>
Studentenlizenzen € 23,74



Matcad Prime 2.0 - [AKADEMISCH] - C:\VorlesungenRd\Elektronik\Elektronik_I_13_14\KW042\Mi_Einfuehrung\beam_propagation_1.mcdx

Rechnen Eingabe/Ausgabe Funktionen Matrizen/Tabellen Diagramme Formatierung Berechnung Dokument Erste Schritte

Rechnen Lösungsblock Textblock Textfeld Bild Bereich löschen Operatoren Symbole Programmierung Konstanten Symbolische Mathematik

Bereiche Operatoren und Symbole Stil Einheiten Zwischenablage

beam_propagation_1

Berechnung der Fokuszposition einer Linsencombination

$$M_d(d) := \begin{bmatrix} 1 & d \\ 0 & 1 \end{bmatrix} \quad M_f(f) := \begin{bmatrix} 1 & 0 \\ -\frac{1}{f} & 1 \end{bmatrix}$$

Gleichungs- / Nebenbedingungs- / geschätzte werte

$$d_{2f} := 150 \quad r_1 := \begin{bmatrix} 0.1 \\ 0 \end{bmatrix}$$

$$r_1 = M_d(d_{2f}) \cdot M_f(-150) \cdot M_d(d_{12}) \cdot M_f(200) \cdot r_0$$

$$r_1 \hat{=} 0$$

$$\begin{bmatrix} d_{2f} \\ r_1 \end{bmatrix} := \text{find}(d_{2f}, r_1)$$

Berechnung von w0 aus λ und der "Divergenz", also der Neigung r'

$$d_{2f} = 240.6 \quad r_1 = \begin{bmatrix} 7.551 \cdot 10^{-20} \\ -0.004 \end{bmatrix}$$

$$d_{tot} := d_{12} + d_{2f} = 365.6 \quad w_0 := \frac{\lambda}{\pi \cdot \left(-r_1 \frac{2}{\lambda}\right)} \cdot M2 = [38.9] \mu\text{m}$$

LF155/LF156/LF157 Series Monolithic JFET Input Operational Amplifiers

December 1994

National Semiconductor

LF155/LF156/LF157 Series Monolithic JFET Input Operational Amplifiers

General Description

These are the first monolithic JFET input operational amplifiers to incorporate well matched, high voltage JFETs on the same chip with standard bipolar transistors (Bi-FET™ Technology). These amplifiers feature low input bias and offset currents/low offset voltage and offset voltage drift, coupled with offset adjust which does not degrade drift or common-mode rejection. The devices are also designed for high slew rate, wide bandwidth, extremely fast settling time, low voltage and current noise and a low 1/f noise corner.

Advantages

- Replace expensive hybrid and module FET op amps
- Rugged JFETs allow blow-out free handling compared with MOSFET input devices
- Excellent for low noise applications using either high or low source impedance—very low 1/f corner
- Offset adjust does not degrade drift or common-mode rejection as in most monolithic amplifiers
- New output stage allows use of large capacitive loads (5,000 pF) without stability problems
- Internal compensation and large differential input voltage capability

Applications

- Precision high speed integrators
- Fast D/A and A/D converters
- High impedance buffers
- Wideband, low noise, low drift amplifiers
- Logarithmic amplifiers

Common Features

- Photocell amplifiers
- Sample and Hold circuits

Common Features

- Low input bias current
- Low Input Offset Current
- High input impedance
- Low input offset voltage
- Low input offset voltage temp. drift
- Low input noise current
- High common-mode rejection ratio
- Large dc voltage gain

	LF155A	LF156A	LF157A	Units
(A _V = 5)	4	1.5	1.5	μs
Fast slew rate	5	12	50	V/μs
Wide gain bandwidth	2.5	5	20	MHz
Low input noise voltage	20	12	12	nV/√Hz

Uncommon Features

- Extremely fast settling time to 0.01%
- Fast slew rate
- Wide gain bandwidth
- Low input noise voltage

Simplified Schematic

*3 pF in LF157 series.

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RFD-830M115 Printed in U.S.A.

DC Electrical Characteristics (Note 3) $T_A = T_J = 25^\circ\text{C}$ (Continued)

Symbol	Parameter	Conditions	LF155A/6A/7A			LF355A/6A/7A			Units
			Min	Typ	Max	Min	Typ	Max	
V_{CM}	Input Common-Mode Voltage Range	$V_S = \pm 15\text{V}$	± 11	+15.1 -12	± 11	+15.1 -12		V V	
CMRR	Common-Mode Rejection Ratio	(Note 6)	85	100	85	100		dB	
PSRR	Supply Voltage Rejection Ratio	(Note 6)	85	100	85	100		dB	

AC Electrical Characteristics $T_A = T_J = 25^\circ\text{C}$, $V_S = \pm 15\text{V}$

Symbol	Parameter	Conditions	LF155A/355A			LF156A/356A			LF157A/357A			Units
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
SR	Slew Rate	LF155A/6A: $A_V = 1$, LF157A: $A_V = 5$	3	5	10	12	40	50			V/ μs V/ μs	
GBW	Gain Bandwidth Product	(Note 7)	2.5	4	4	4.5	15	20			MHz	
t_s	Settling Time to 0.01%	(Note 7)	4	1.5	1.5		1.5				μs	
e_n	Equivalent Input Noise Voltage	$R_S = 100\Omega$ $f = 100\text{ Hz}$ $f = 1000\text{ Hz}$	25	20	15	12	15	12	15	12	nV/ $\sqrt{\text{Hz}}$ nV/ $\sqrt{\text{Hz}}$	
i_n	Equivalent Input Noise Current	$f = 100\text{ Hz}$ $f = 1000\text{ Hz}$	0.01	0.01	0.01	0.01	0.01	0.01	0.01	0.01	pA/ $\sqrt{\text{Hz}}$ pA/ $\sqrt{\text{Hz}}$	
C_{IN}	Input Capacitance		3	3	3	3	3	3			pF	

DC Electrical Characteristics (Note 3)

Symbol	Parameter	Conditions	LF155/6/7			LF255/6/7			LF355/6/7			Units
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
V_{OS}	Input Offset Voltage	$R_S = 500\Omega$, $T_A = 25^\circ\text{C}$ Over Temperature	3	5	3	5	3	5	3	10	13	mV mV
$\Delta V_{OS}/\Delta T$	Average TC of Input Offset Voltage	$R_S = 500\Omega$	5		5		5		5		$\mu\text{V}/^\circ\text{C}$	
$\Delta TC/\Delta V_{OS}$	Change in Average TC with V_{OS} Adjust	$R_S = 500\Omega$, (Note 4)	0.5		0.5		0.5		0.5		$\mu\text{V}/^\circ\text{C}$ per mV	
I_{OS}	Input Offset Current	$T_J = 25^\circ\text{C}$, $T_J \leq T_{HIGH}$	3	20	3	20	3	20	3	50	pA nA	
I_B	Input Bias Current	$T_J = 25^\circ\text{C}$, (Notes 3, 5) $V_O = \pm 10\text{V}$, $R_L = 2\text{k}\Omega$ Over Temperature	30	100	30	100	30	100	30	200	pA nA	
R_{IN}	Input Resistance	$T_J = 25^\circ\text{C}$	10 ¹²		10 ¹²		10 ¹²		10 ¹²		Ω	
A_{VOL}	Large Signal Voltage Gain	$V_S = \pm 15\text{V}$, $T_A = 25^\circ\text{C}$ $V_O = \pm 10\text{V}$, $R_L = 2\text{k}\Omega$ Over Temperature	50	200	50	200	25	200	25	200	V/mV V/mV	
V_O	Output Voltage Swing	$V_S = \pm 15\text{V}$, $R_L = 10\text{k}\Omega$ $V_S = \pm 15\text{V}$, $R_L = 2\text{k}\Omega$	± 12 ± 10	± 13 ± 12	± 12 ± 10	± 13 ± 12	± 12 ± 10	± 13 ± 12	± 13 ± 12	± 13 ± 12	V V	
V_{CM}	Input Common-Mode Voltage Range	$V_S = \pm 15\text{V}$	± 11 -12	± 15.1 -12	± 11 -12	± 15.1 -12	± 11 -12	± 15.1 -12	± 11 -12	± 15.1 -12	V V	
CMRR	Common-Mode Rejection Ratio	(Note 6)	85	100	85	100	80	100	80	100	dB	
PSRR	Supply Voltage Rejection Ratio	(Note 6)	85	100	85	100	80	100	80	100	dB	

Absolute Maximum Ratings

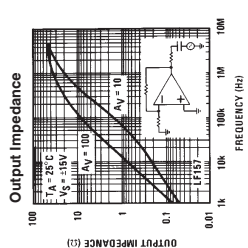
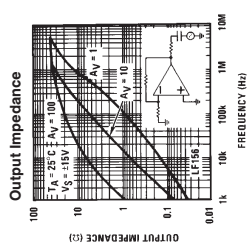
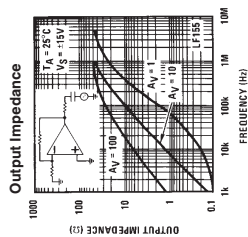
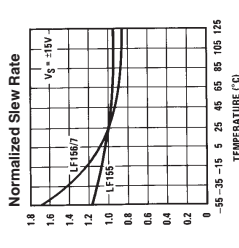
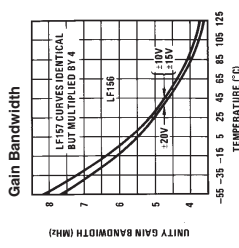
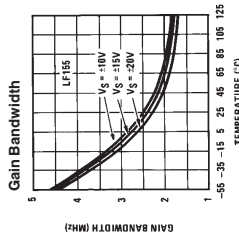
If Military/Aerospace specified devices are required, contact the National Semiconductor Sales Office/Distributors for availability and specifications. (Note 8)

Supply Voltage	Differential Input Voltage	Input Voltage Range (Note 2)	Output Short Circuit Duration	T_{JMAX}	H-Package	N-Package	M-Package	Power Dissipation at $T_A = 25^\circ\text{C}$ (Notes 1 and 9)	H-Package (SIII Air)	H-Package (400 LF/Min Air Flow)	M-Package	Thermal Resistance (Typical) θ_{JA}	H-Package (SIII Air)	H-Package (400 LF/Min Air Flow)	N-Package	(Typical) θ_{JC}	H-Package	Storage Temperature Range	Soldering Information (Lead Temp.)	Metal Can Package	Dual-In-Line Package	Soldering (10 sec.)	Small Outline Package	Vapor Phase (60 sec.)	Infrared (15 sec.)	See AN-450 "Surface Mounting Methods and Their Effect on Product Reliability" for other methods of soldering surface mount devices.	ESD tolerance	(100 pF discharged through 1.5 k Ω)
$\pm 22\text{V}$	$\pm 40\text{V}$	$\pm 20\text{V}$	Continuous	150 $^\circ\text{C}$	150 $^\circ\text{C}$	150 $^\circ\text{C}$	150 $^\circ\text{C}$	560 mW 1200 mW	660 mW 1200 mW	660 mW 1200 mW	380 mW	160 $^\circ\text{C}/\text{W}$ 65 $^\circ\text{C}/\text{W}$	160 $^\circ\text{C}/\text{W}$ 65 $^\circ\text{C}/\text{W}$	160 $^\circ\text{C}/\text{W}$ 65 $^\circ\text{C}/\text{W}$	160 $^\circ\text{C}/\text{W}$ 65 $^\circ\text{C}/\text{W}$	23 $^\circ\text{C}/\text{W}$	23 $^\circ\text{C}/\text{W}$	-65 $^\circ\text{C}$ to +150 $^\circ\text{C}$	-65 $^\circ\text{C}$ to +150 $^\circ\text{C}$	300 $^\circ\text{C}$	300 $^\circ\text{C}$	260 $^\circ\text{C}$	215 $^\circ\text{C}$	220 $^\circ\text{C}$	1000V	1000V	1000V	
$\pm 18\text{V}$	$\pm 30\text{V}$	$\pm 16\text{V}$	Continuous	115 $^\circ\text{C}$	115 $^\circ\text{C}$	100 $^\circ\text{C}$	100 $^\circ\text{C}$	400 mW 1000 mW 670 mW 380 mW	400 mW 1000 mW 670 mW 380 mW	400 mW 1000 mW 670 mW 380 mW	380 mW	160 $^\circ\text{C}/\text{W}$ 65 $^\circ\text{C}/\text{W}$	160 $^\circ\text{C}/\text{W}$ 65 $^\circ\text{C}/\text{W}$	160 $^\circ\text{C}/\text{W}$ 65 $^\circ\text{C}/\text{W}$	160 $^\circ\text{C}/\text{W}$ 65 $^\circ\text{C}/\text{W}$	23 $^\circ\text{C}/\text{W}$	23 $^\circ\text{C}/\text{W}$	-65 $^\circ\text{C}$ to +150 $^\circ\text{C}$	-65 $^\circ\text{C}$ to +150 $^\circ\text{C}$	300 $^\circ\text{C}$	300 $^\circ\text{C}$	260 $^\circ\text{C}$	215 $^\circ\text{C}$	220 $^\circ\text{C}$	1000V	1000V	1000V	

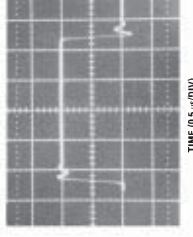
DC Electrical Characteristics (Note 3) $T_A = T_J = 25^\circ\text{C}$

Symbol	Parameter	Conditions	LF155A/6A/7A			LF355A/6A/7A			Units		
			Min	Typ	Max	Min	Typ	Max			
V_{OS}	Input Offset Voltage	$R_S = 500\Omega$, $T_A = 25^\circ\text{C}$ Over Temperature		1	2	2.5		1	2	2.3	mV mV
$\Delta V_{OS}/\Delta T$	Average TC of Input Offset Voltage	$R_S = 500\Omega$		3	5			3	5		$\mu\text{V}/^\circ\text{C}$ per mV
$\Delta TC/\Delta V_{OS}$	Change in Average TC with V_{OS} Adjust	$R_S = 500\Omega$, (Note 4)		0.5				0.5			$\mu\text{V}/^\circ\text{C}$ per mV
I_{OS}	Input Offset Current	$T_J = 25^\circ\text{C}$, (Notes 3, 5) $T_J \leq T_{HIGH}$		3	10	10		3	10	1	pA nA
I_B	Input Bias Current	$T_J = 25^\circ\text{C}$, (Notes 3, 5) $T_J \leq T_{HIGH}$		30	50	25		30	50	5	pA nA
R_{IN}	Input Resistance	$T_J = 25^\circ\text{C}$		10 ¹²				10 ¹²			Ω
A_{VOL}	Large Signal Voltage Gain	$V_S = \pm 15\text{V}$, $T_A = 25^\circ\text{C}$ $V_O = \pm 10\text{V}$, $R_L = 2\text{k}\Omega$ Over Temperature	50	200	25			50	200	25	V/mV V/mV
V_O	Output Voltage Swing	$V_S = \pm 15\text{V}$, $R_L = 10\text{k}\Omega$ $V_S = \pm 15\text{V}$, $R_L = 2\text{k}\Omega$	± 12 ± 10	± 13 ± 12	± 12 ± 10	± 13 ± 12	± 12 ± 10	± 13 ± 12	± 13 ± 12	± 13 ± 12	V V

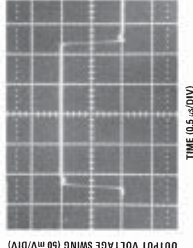
Typical AC Performance Characteristics



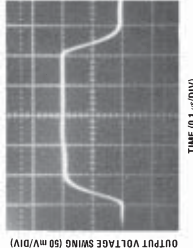
LF155 Small Signal Pulse Response, $A_V = +1$



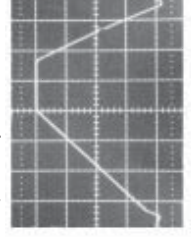
LF156 Small Signal Pulse Response, $A_V = +1$



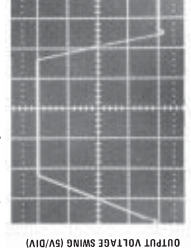
Small Signal Pulse Response, $A_V = +5$



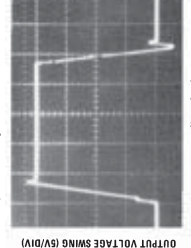
LF155 Large Signal Pulse Response, $A_V = +1$



LF156 Large Signal Pulse Response, $A_V = +1$



LF157 Large Signal Pulse Response, $A_V = +5$



DC Electrical Characteristics

$T_A = T_J = 25^\circ\text{C}, V_S = \pm 15\text{V}$

Parameter	LF155A/155, LF255, LF355A/355B		LF355		LF156A/156, LF256/256B, LF356A/356B		LF157A/157, LF257/257B, LF357A/357B		Units		
	Typ	Max	Typ	Max	Typ	Max	Typ	Max	Typ	Max	
Supply Current	2	4	2	4	5	7	5	10	5	7	mA

AC Electrical Characteristics

$T_A = T_J = 25^\circ\text{C}, V_S = \pm 15\text{V}$

Symbol	Parameter	Conditions	LF155/255/355/355B		LF156/256/356/356B		LF157/257/357/357B		Units
			Typ	Min	Typ	Min	Typ	Min	
SR	Slew Rate	LF155/6: $A_V = 1$, LF157: $A_V = 5$	5	7.5	12	12	30	50	V/ μs
GBW	Gain Bandwidth Product		2.5		5		20		MHz
t_s	Settling Time to 0.01% (Note 7)		4		1.5		1.5		μs
e_n	Equivalent Input Noise Voltage	$R_S = 100\Omega$, $f = 100\text{ Hz}$, $f = 1000\text{ Hz}$	25		15		15		nV/ $\sqrt{\text{Hz}}$
i_n	Equivalent Input Current Noise	$f = 100\text{ Hz}$, $f = 1000\text{ Hz}$	0.01		0.01		0.01		pA/ $\sqrt{\text{Hz}}$
C_{IN}	Input Capacitance		3		3		3		pF

Notes for Electrical Characteristics

Note 1: The maximum power dissipation for these devices must be derated at elevated temperatures and is dictated by T_{JMAX} , θ_{JA} , and the ambient temperature, T_A . The maximum available power dissipation at any temperature is $P_{JM} = (T_{JMAX} - T_A)/\theta_{JA}$ or the $25^\circ\text{C } P_{JM,MAX}$, whichever is less.

Note 2: Unless otherwise specified the absolute maximum negative input voltage is equal to the negative power supply voltage.

Note 3: Unless otherwise stated, these test conditions apply.

Supply Voltage, V_S	LF155A/6A/7A, LF155/157		LF255/157		LF355B/6B/7B		LF355/157	
	Typ	Max	Typ	Max	Typ	Max	Typ	Max
T_A	$\pm 15\text{V} \leq V_S \leq \pm 20\text{V}$	$-25^\circ\text{C} \leq T_A \leq +85^\circ\text{C}$	$\pm 15\text{V} \leq V_S \leq \pm 20\text{V}$	$0^\circ\text{C} \leq T_A \leq +70^\circ\text{C}$	$\pm 15\text{V} \leq V_S \leq \pm 20\text{V}$	$0^\circ\text{C} \leq T_A \leq +70^\circ\text{C}$	$\pm 15\text{V} \leq V_S \leq \pm 20\text{V}$	$0^\circ\text{C} \leq T_A \leq +70^\circ\text{C}$
T_{HIGH}	$+125^\circ\text{C}$	$+85^\circ\text{C}$	$+125^\circ\text{C}$	$+85^\circ\text{C}$	$+70^\circ\text{C}$	$+70^\circ\text{C}$	$+70^\circ\text{C}$	$+70^\circ\text{C}$

Note 4: The Temperature Coefficient of the adjusted input offset voltage changes only a small amount (0.51mV/ $^\circ\text{C}$ typically) for each mV of adjustment from its original unadjusted value. Common-mode rejection and open loop voltage gain are also unaffected by offset adjustment.

Note 5: The input bias currents are junction leakage currents which approximately double for every 10°C increase in the junction temperature, T_J . Due to limited production test time, the input bias currents measured are correlated to junction temperature. In normal operation the junction temperature rises above the ambient temperature as a result of internal power dissipation, $P_{d} = T_J \times \theta_{JA}$, P_{d} where θ_{JA} is the thermal resistance from junction to ambient. Use of a heat sink is recommended if input bias current is to be kept to a minimum.

Note 6: Supply Voltage Rejection is measured for both supply magnitudes increasing or decreasing simultaneously, in accordance with common practice.

Note 7: Settling time is defined here, for a unity gain inverter connection using 2 k Ω resistors for the LF155/6. It is the time required for the error voltage (the voltage at the inverting input pin) to settle to within 0.01% of its final value from the time a step input is applied to the inverter. For the LF157, $A_V = 5$, the feedback resistor from output to input is 2 k Ω and the output step is 10V (See Settling Time Test Circuit).

Note 8: Refer to REITS155AX for LF155A, REITS155X for LF155, REITS156AX for LF156A, REITS156X for LF156, REITS157A for LF157A and REITS157X for LF157 military specifications.

Note 9: Max. Power Dissipation is defined by the package characteristics. Operating the part near the Max. Power Dissipation may cause the part to operate outside guaranteed limits.

Application Hints

The LF155/6/7 series are op amps with JFET input devices. These JFETs have large reverse breakdown voltages from gate to source and drain eliminating the need for clamps across the inputs. Therefore large differential input voltages can easily be accommodated without a large increase in input current. The maximum differential input voltage is independent of the supply voltages. However, neither of the input voltages should be allowed to exceed the negative supply as this will cause large currents to flow which can result in a destroyed unit.

Exceeding the negative common-mode limit on either input will force the output to a high state, potentially causing a reversal of phase to the output. Exceeding the negative common-mode limit on both inputs will force the amplifier output to a high state. In neither case does a latch occur since raising the input back within the common-mode range again puts the input stage and thus the amplifier in a normal operating mode.

Exceeding the positive common-mode limit on a single input will not change the phase of the output; however, if both inputs exceed the limit, the output of the amplifier will be forced to a high state.

These amplifiers will operate with the common-mode input voltage equal to the positive supply. In fact, the common-mode voltage can exceed the positive supply by approximately 100 mV independent of supply voltage and over the full operating temperature range. The positive supply can therefore be used as a reference on an input as, for example, in a supply current monitor and/or limiter.

Precautions should be taken to ensure that the power supply for the integrated circuit never becomes reversed in polarity or that the unit is not inadvertently installed backwards in a socket as an unlimited current surge through the resulting forward diode within the IC could cause fusing of the internal conductors and result in a destroyed unit.

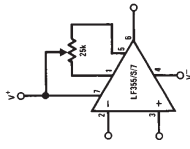
All of the bias currents in these amplifiers are set by FET current sources. The drain currents for the amplifiers are therefore essentially independent of supply voltage.

As with most amplifiers, care should be taken with lead dress, component placement and supply decoupling in order to ensure stability. For example, resistors from the output to an input should be placed with the body close to the input to minimize "pickup" and maximize the frequency of the feedback pole by minimizing the capacitance from the input to ground.

A feedback pole is created when the feedback around any amplifier is resistive. The parallel resistance and capacitance from the input of the device (usually the inverting input) to ac ground set the frequency of the pole. In many instances the frequency of this pole is much greater than the expected 3 dB frequency of the closed loop gain and consequently there is negligible effect on stability margin. However, if the feedback pole is less than approximately six times the expected 3 dB frequency a lead capacitor should be placed from the output to the input of the op amp. The value of the added capacitor should be such that the RC time constant of this capacitor and the resistance it parallels is greater than or equal to the original feedback pole time constant.

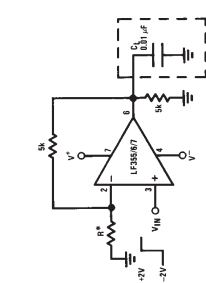
Typical Circuit Connections

Vos Adjustment



- Vos is adjusted with a 25k potentiometer
- The potentiometer wiper is connected to V+
- For potentiometers with temperature coefficient of 100 ppm/°C or less the additional drift with adjust is $\approx 0.5 \mu\text{V}/^\circ\text{C}/\text{mV}$ of adjustment
- Typical overall drift is $5 \mu\text{V}/^\circ\text{C} \pm 0.5 \mu\text{V}/^\circ\text{C}/\text{mV}$ of adj.

Driving Capacitive Loads



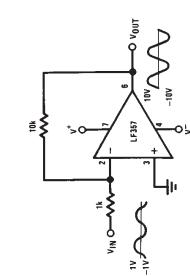
LF155/6 R = 5k
LF157 R = 1.25k

Due to a unique output stage design, these amplifiers have the ability to drive large capacitive loads and still maintain stability. $C_{L(\text{MAX})} \approx 0.01 \mu\text{F}$.

Overshoot $\leq 20\%$

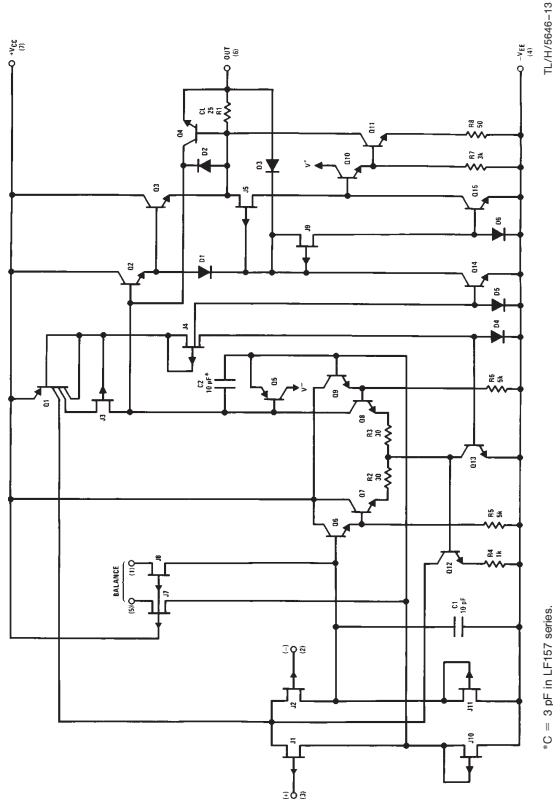
Settling time (t_s) $\approx 5 \mu\text{s}$

LF157, A Large Power BW Amplifier



For distortion $\leq 1\%$ and a 20 Vp-p V_{OUT} swing, power bandwidth is: 500 kHz.

Detailed Schematic

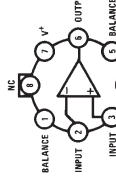


*C = 3 pF in LF157 series.

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Connection Diagrams (Top Views)

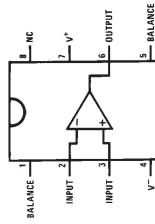
Metal Can Package (H)



Order Number LF156AH, LF155H, LF156H, LF156H, LF255H, LF256H, LF257H, LF355AH, LF356AH, LF357AH, LF356BH, LF355BH, LF356H, LF357H, LM155AH/883, LM156H/883, LM156AH/883, LM157AH/883, LM157H/883

See NS Package Number H08C

Dual-In-Line Package (M and N)

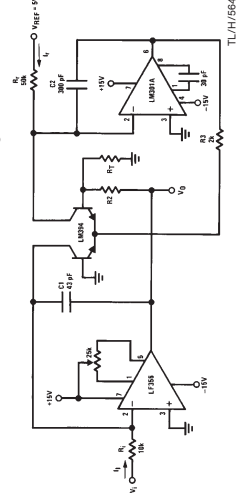


Order Number LF355M, LF356M, LF357M, LF355BM, LF356BM, LF355BN, LF356BN, LF357BN, LF355N, LF356N or LF357N

See NS Package Number M08A or N08E

Typical Applications (Continued)

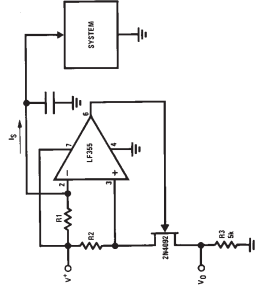
Fast Logarithmic Converter



TL/H/5646-21

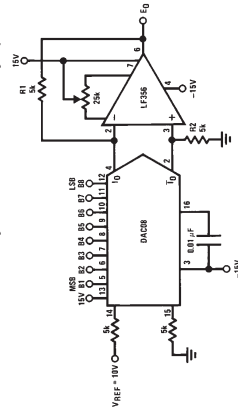
$$|V_{out}| = \left[1 + \frac{R_2}{R_1} \ln \left(\frac{R_4}{R_3} \right) \right] \log \left(\frac{V_i}{V_{REF}} \right) = \log V_i \left[\frac{R_2}{R_1} \ln \left(\frac{R_4}{R_3} \right) + 1 \right] \quad \text{for temperature compensation}$$

Precision Current Monitor



TL/H/5646-31

8-Bit D/A Converter with Symmetrical Offset Binary Operation



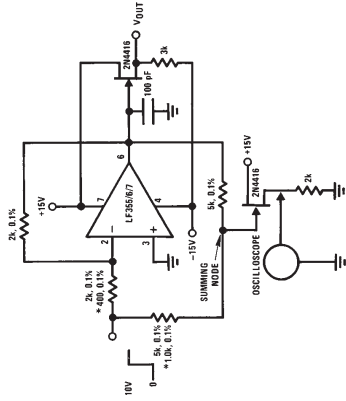
TL/H/5646-32

- R1, R2 should be matched within $\pm 0.05\%$
- Full-scale response time: 9 μ s

E_0	B1	B2	B3	B4	B5	B6	B7	B8	Comments
+9.920	1	1	1	1	1	1	1	1	Positive Full-Scale
+0.040	1	0	0	0	0	0	0	0	(+) Zero-Scale
-0.040	0	1	1	1	1	1	1	0	(-) Zero-Scale
-9.920	0	0	0	0	0	0	0	0	Negative Full-Scale

Typical Applications

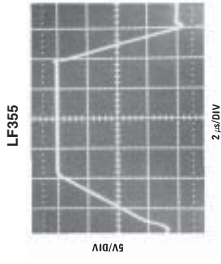
Setting Time Test Circuit



TL/H/5646-16

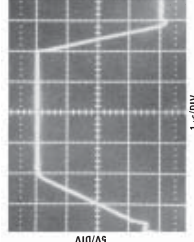
- Settling time is tested with the LF157/6 connected as unity gain inverter and LF157 connected for $A_v = -5$
- FET used to isolate the probe capacitance
- Output = 10V step
- $A_v = -5$ for LF157

Large Signal Inverter Output, Vout (from Setting Time Circuit)



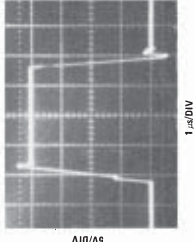
LF355

TL/H/5646-17



LF356

TL/H/5646-18

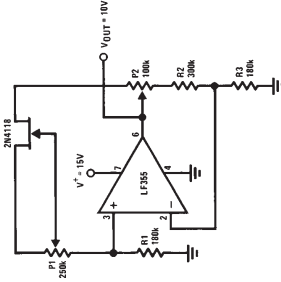


LF357

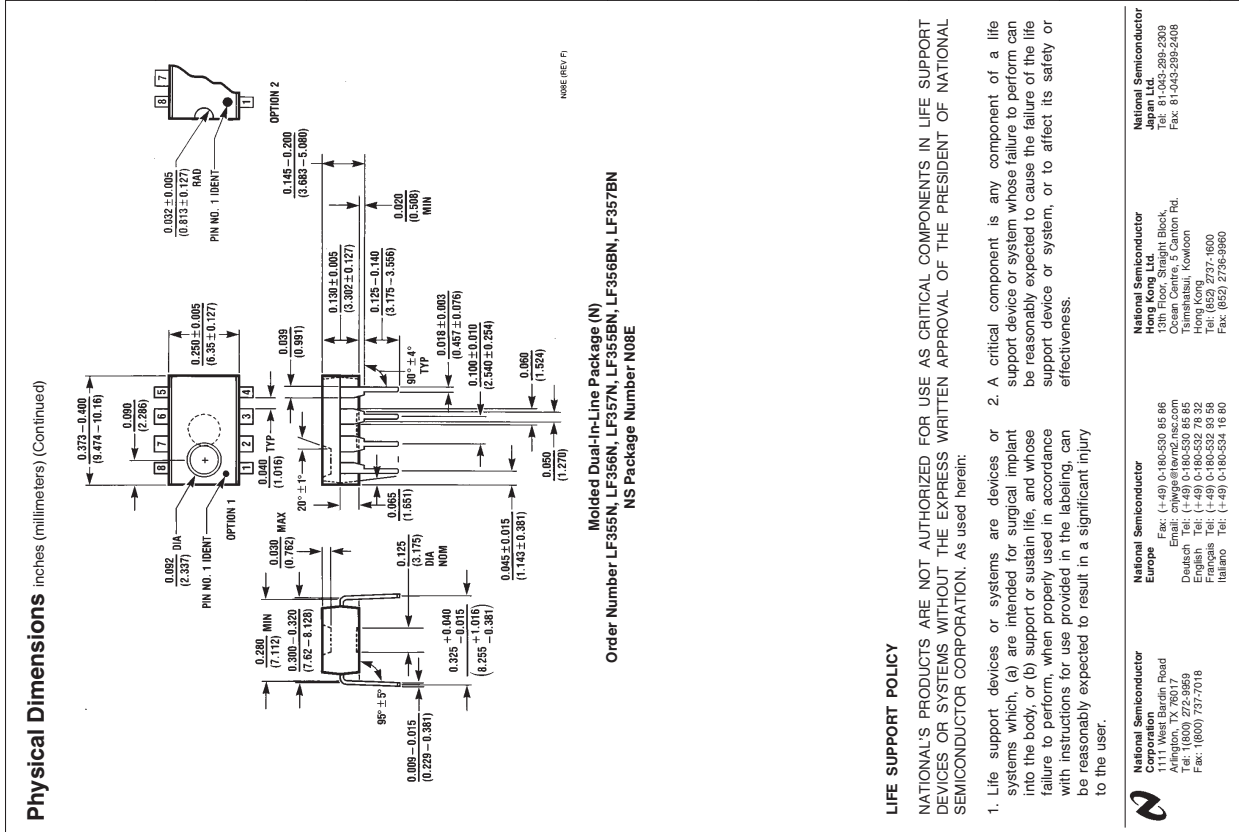
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Low Drift Adjustable Voltage Reference

- $\Delta V_{OUT}/\Delta T = \pm 0.002\%/^{\circ}\text{C}$
- All resistors and potentiometers should be wire-wound
- P1: drift adjust
- P2: Vout adjust
- Use LF155 for
 - Low lb
 - Low drift
 - Low supply current



TL/H/5646-20



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Elektronik mit Steckbrett und Lötkolben

WS 2017/18

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What do we want to do ?

- In der Experimentalphysik spielt die **Instrumententwicklung** eine große Rolle. Auch wenn in einem Aufbau oft kommerzielle Module oder Komponenten zum Einsatz kommen, erfordert die logische Verschaltung durch Triggersignale und das schnelle Steuern und Regeln Grundkenntnisse in der elektronischen Signalverarbeitung. In vielen Fällen ist es auch zweckmäßig, kleine Schaltkreise (z.B. Filter) oder programmierbare Mikroprozessoren (z.B. Arduino) zu verwenden, um träge Softwarelösungen zu vermeiden. Weiterhin gibt es eine Reihe von wichtigen Messmethoden, insbesondere Lock in-Techniken, die weit verbreitet sind für die Auslese schwacher Signale in Gegenwart von Rauschen, die in den bisherigen Praktika aber leider nicht abgedeckt sind.
- Im Kurs wird der **Aufbau kleiner Schaltungen praktisch erprobt**. Vom einfachen Aufbau auf einem Steckbrett entwickeln wir uns zur gelöteten Platine bis hin zum Layout für geätzte Platinen. Zur Untersuchung der Schaltungen und zum Finden von Fehlern werden modernste **Oszillographen und Funktionsgeneratoren** verwendet.
- Ziel ist es, am Ende **eigene kleine Module aufzubauen**, die für spätere Praktikumsgruppen oder Forschungslabore funktionsfähig zur Verfügung stehen.

What does that really mean?

- Ich plane derzeit, das Praktikum an "Projekten" zu orientieren. Am Anfang müssen die Teilnehmer mal die **Messinstrumente** kennen lernen, gerade das **Picoscope** hat ja sehr viele Möglichkeiten. Hier werden wir verschiedene Wechselspannungsquellen mit passiven und aktiven Methoden überlagern.
- Danach planen wir einen Block zu **3-Weg-Lautsprechern**. Wir werden sowohl passive als auch aktive **Frequenzweichen** bauen. Hier sehen Sie schon, dass nach oben viel Luft ist. Wer schon Erfahrung hat, kann sich ja an Tschebyscheff-Filtern höherer Ordnung versuchen, andere sind sicher mit etwas einfacheren ausgelastet.
- Als nächstes sollten wir etwas zu **Hochfrequenz** machen, da denken wir noch über die genauen Themen nach. Ein Beispiel, das ich gerade selbst bearbeite, ist ein Schmitt-Trigger mit wenigstens 100 MHz Bandbreite.
- Zum Ende würde ich gerne eine Schaltung entwickeln, mit der man **Hochleistungs-LEDs mit gewähltem Spitzenstrom und Pulslänge sowie Taktverhältnis betreibt**. Dabei kann man z.B. auch noch eine Leistungsstabilisierung mit optischer Detektion hinzufügen.

The real thing



Let's get started

